

**INFORMATION
DISCLOSURE STATEMENT
TRANSMITTAL**

To Commissioner For Patents

Enclosed herewith is a Form PTO-1449, any required copies of documents listed thereon, and any concise explanation of their relevance is indicated below per 37 CFR 1.97.

<i>Application Number</i>	
<i>Filing Date</i>	
<i>First Named Inventor</i>	VAN BEEK, JOZEF T., M.
<i>Group Art Unit</i>	
<i>Examiner Name</i>	
<i>Atty. Docket Number</i>	NL03 1310 US1

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Document Number No.-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns Lines, Where Relevant Passages or Relevant Figures Appear
	1	US- US 2004/077119	04/22/2004	IKEDA KOICHI ET AL.	
		US-			
		US-			

FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Document Number (ctry ³ -no. ⁴ -kind ⁵ , if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of cited document	Pages, Columns Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
	1	WO/03078299	09/25/2003	IONESCU, MIHAI ADRIAN ET AL.		
	2	WO 03/055789	07/10/2003	IKEDA KOICHI ET AL		
	3	WO 01/48795	07/05/2001	KUMAR AJAY ET AL.		

NON-PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No. ¹	Include name of the author (in capital letters), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ⁶
	1	FRITSCHI R ET AL: "A NOVEL RF MEMS TECHNOLOGICAL PLATFORM"; IECON-2002 PROCEEDINGS OF THE 28 TH ANNUAL CONFERENCE OF THE IEEE INDUSTRIAL ELECTRONICS SOCIETY"; SEVILLA SPAIN; NOV. 5-8, 2002; ANNUAL CONF. OF IEEE NEW YORK; VOL. 1 OF 4 CONF. 28; 11/5/2002; PP 3052-3056	
	2	CHANG C ET AL: "INNOVATIVE MICROMACHINED MICROWAVE SWITCH WITH VERY LOW INSERTION LOSS"; SENSORS AND ACTUATORS A, ELSEVIER SEQUOIA S.A. LAUSANNE; CH VOL. 79 NO. 1; JAN 2000; PP 71-75	

Examiner Signature		Date Considered	
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* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹Unique citation designation number. ²See attached Kinds of U.S. Patent Documents. ³Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶Applicant is to place a check mark here if English language Translation is attached.